

Applicant(s): Alan Wong et al.

OPTICAL METROLOGY TARGET DESIGN FOR  
SIMULTANEOUS MEASUREMENT OF MULTIPLE PERIODIC  
STRUCTURES

Figure 1.

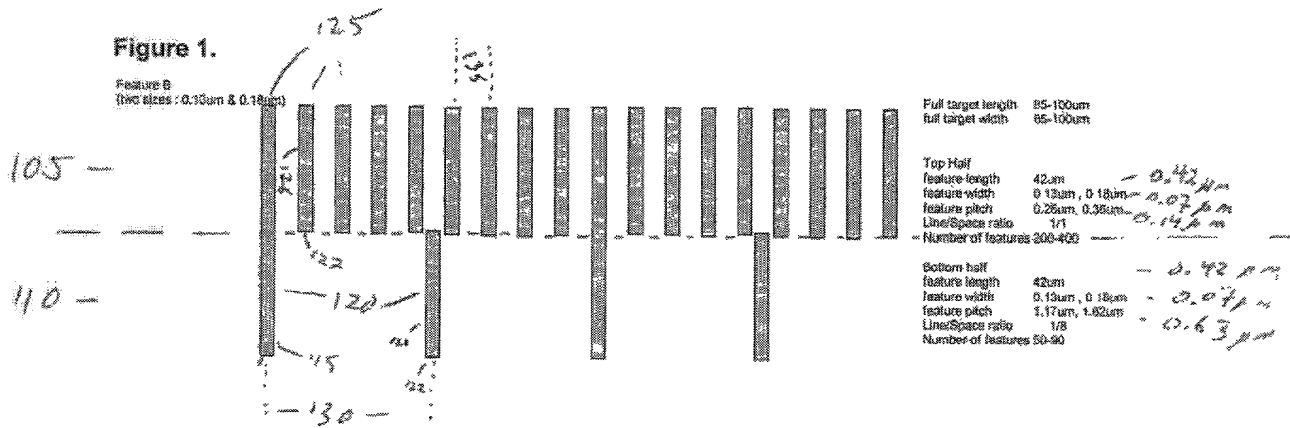
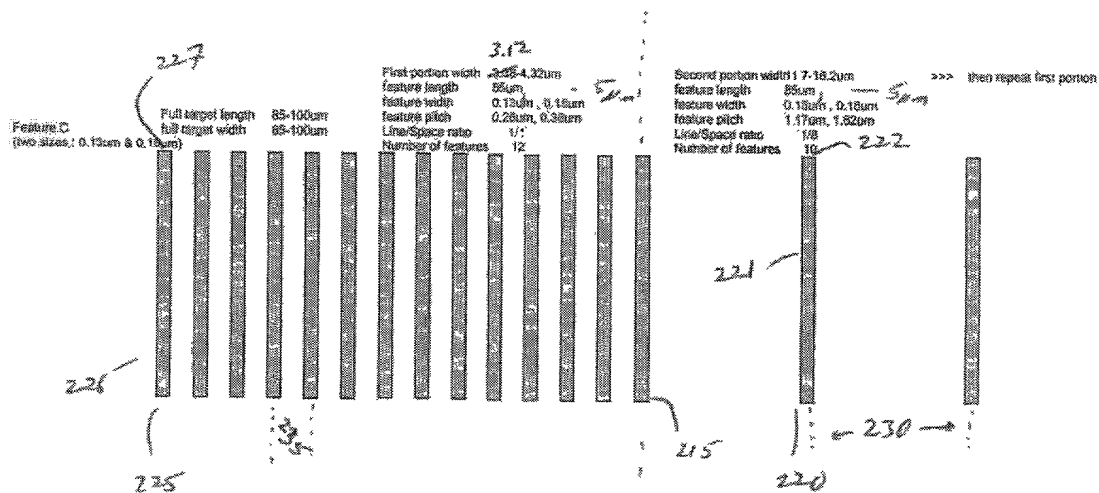
Feature B  
(two sizes: 0.10um & 0.18um)

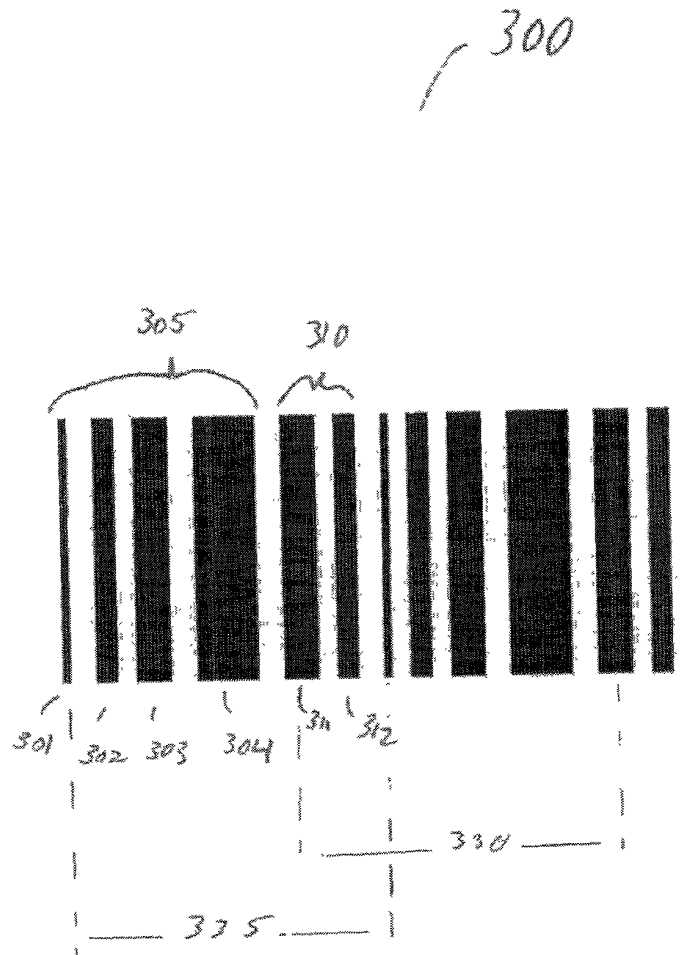
Figure 2.



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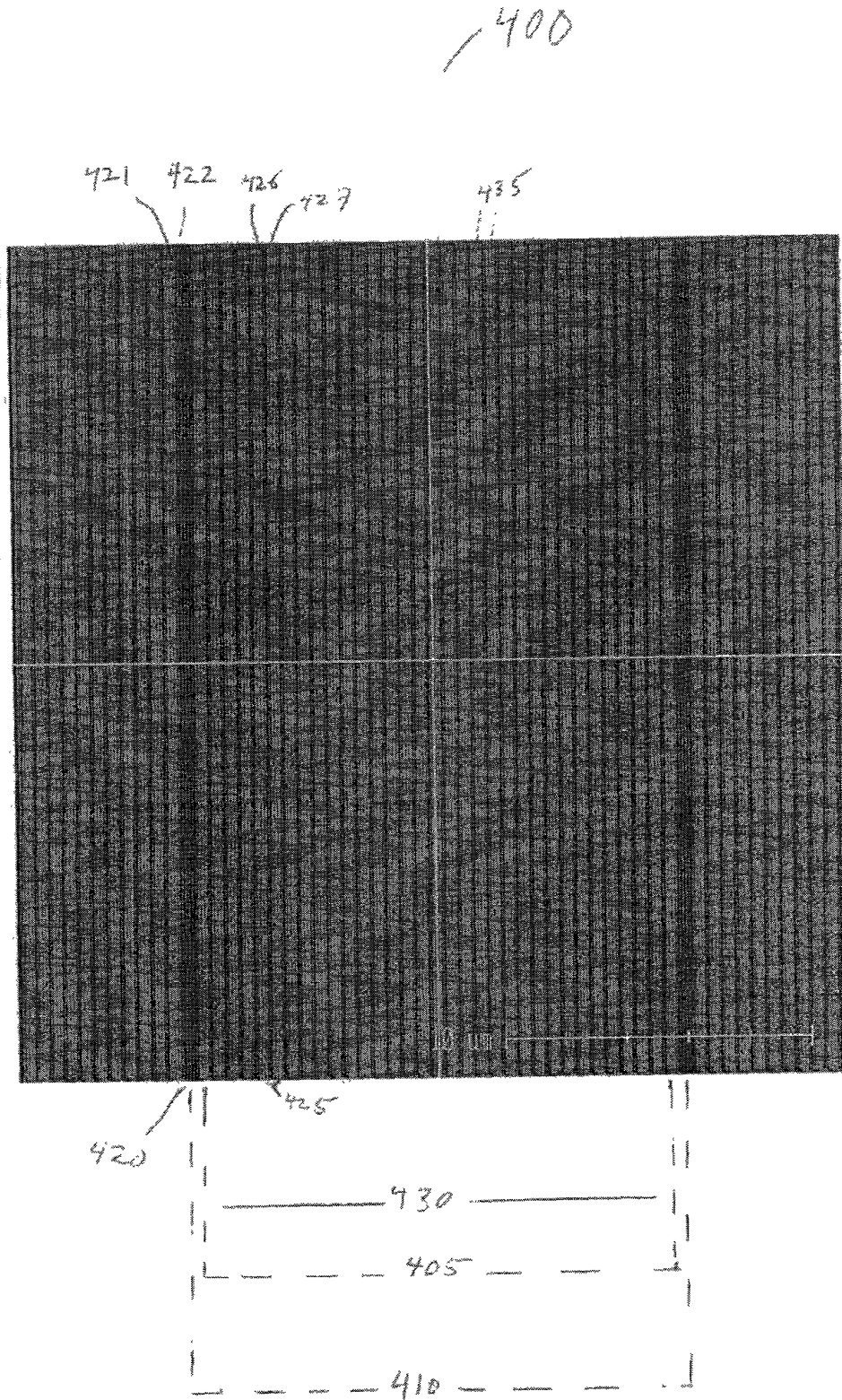
Figure 3.



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Figure 4.



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# OPTICAL METROLOGY TARGET DESIGN FOR SIMULTANEOUS MEASUREMENT OF MULTIPLE PERIODIC STRUCTURES

Fig 5

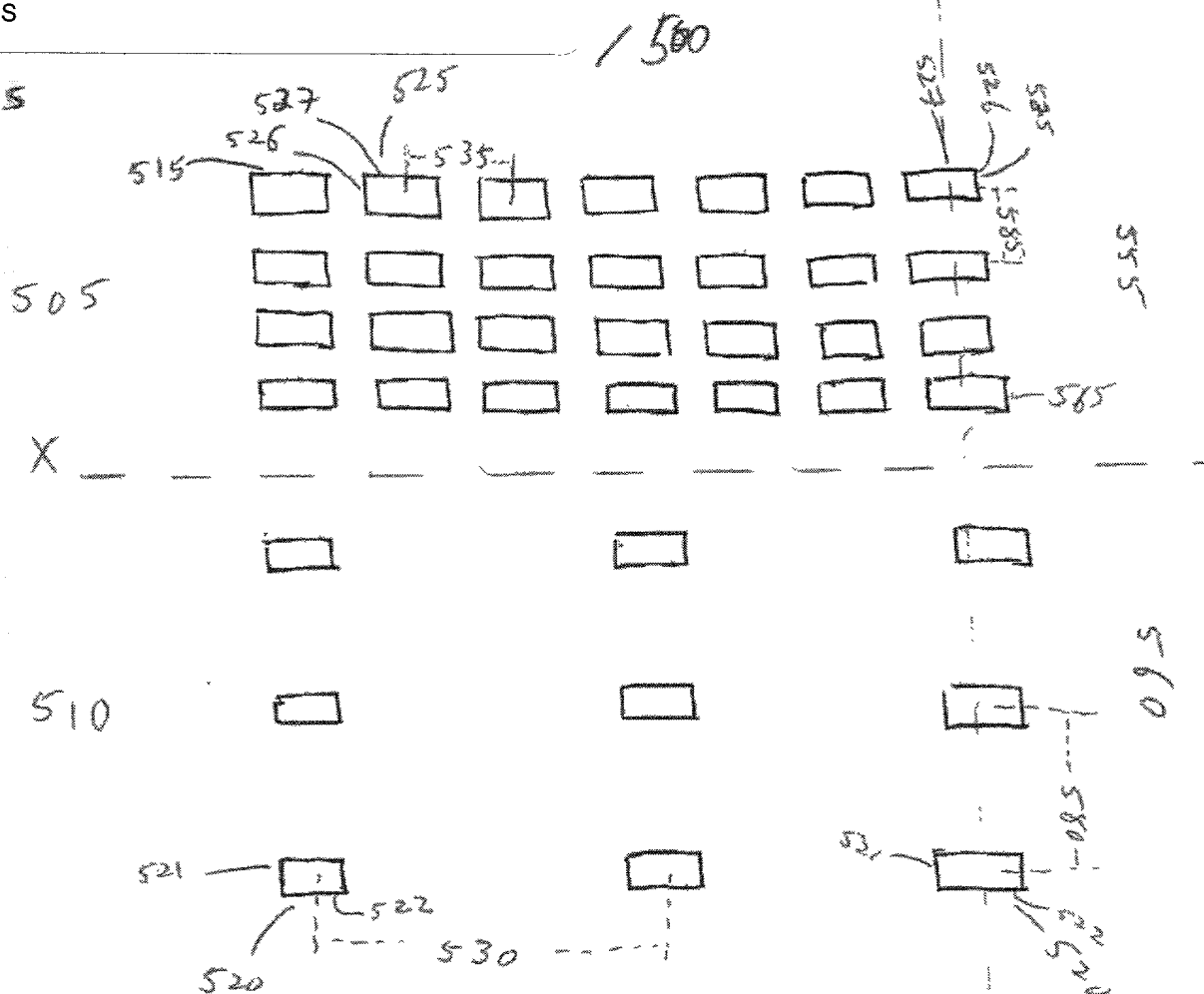
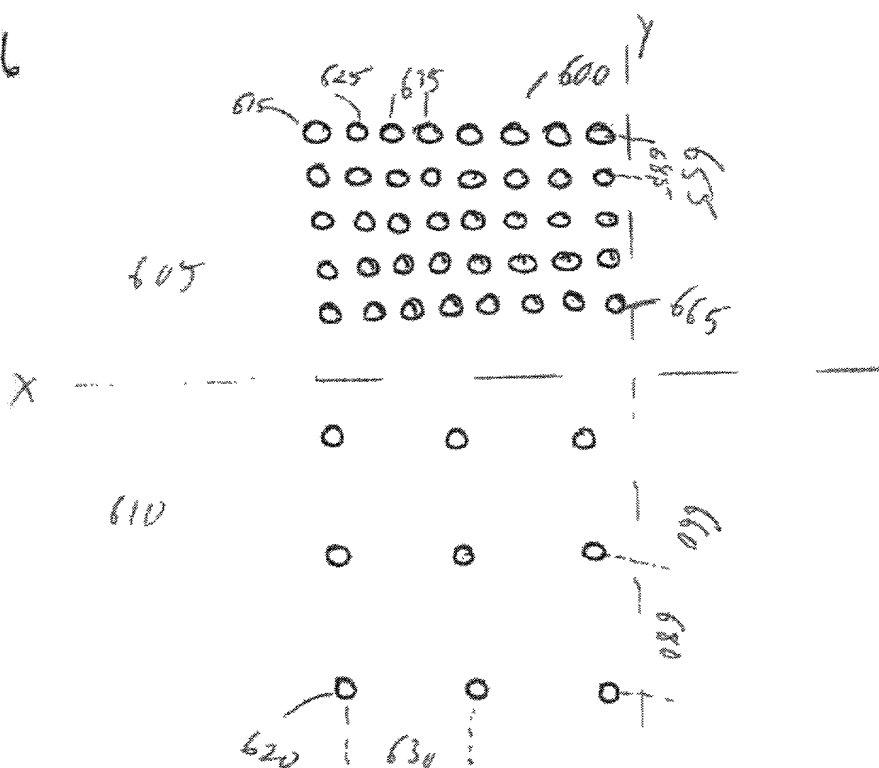


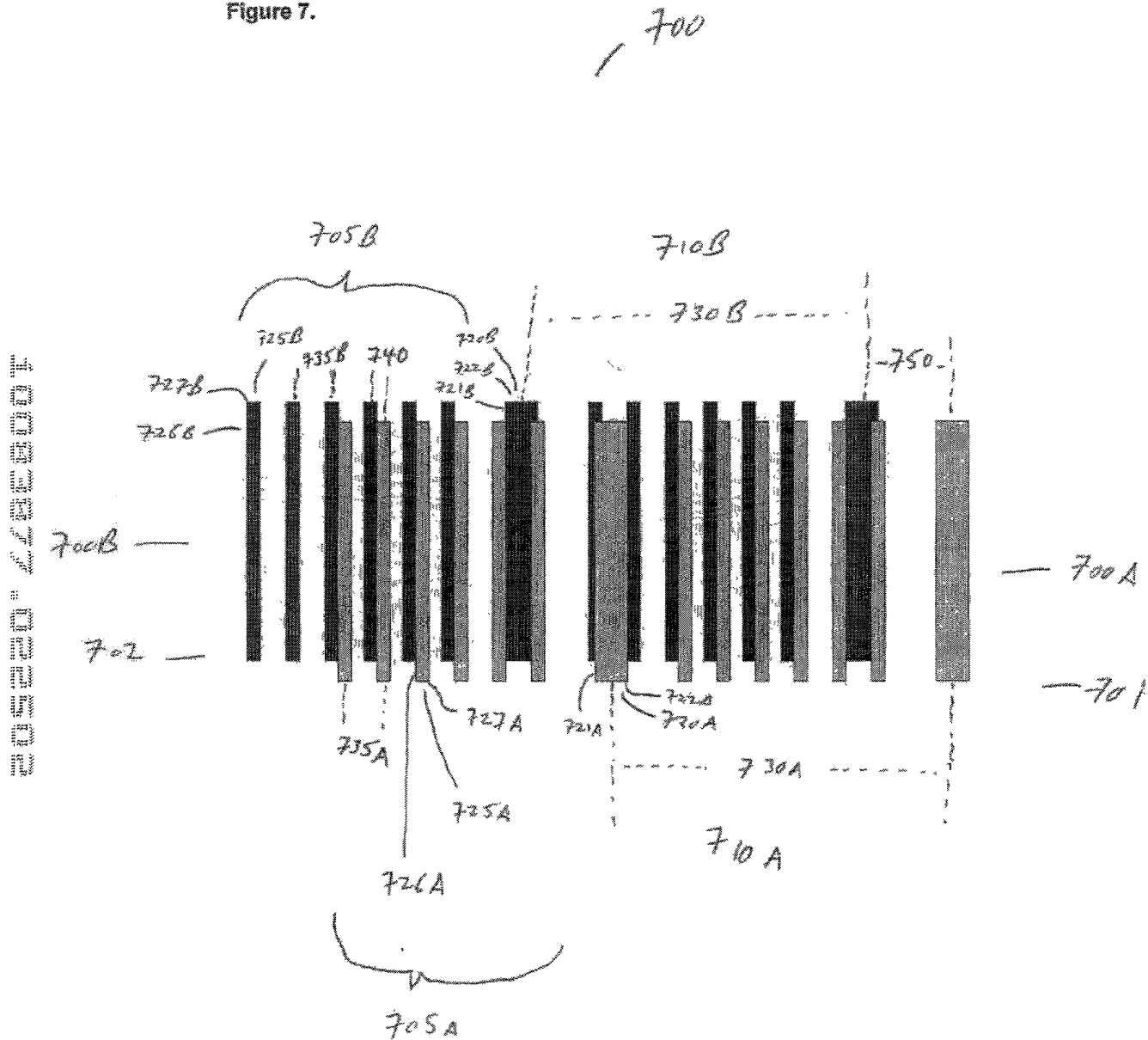
Fig. 6



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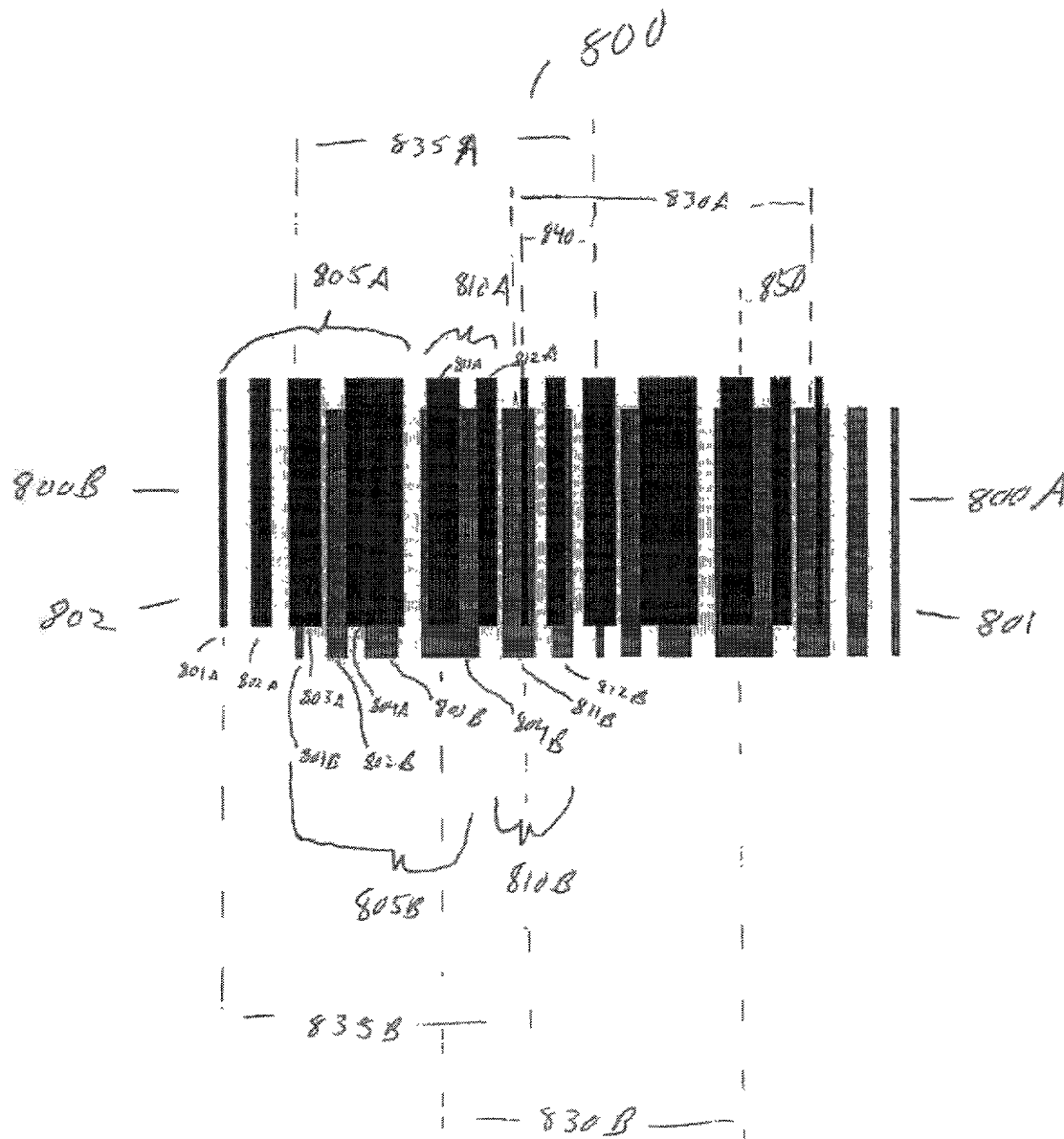
Figure 7.



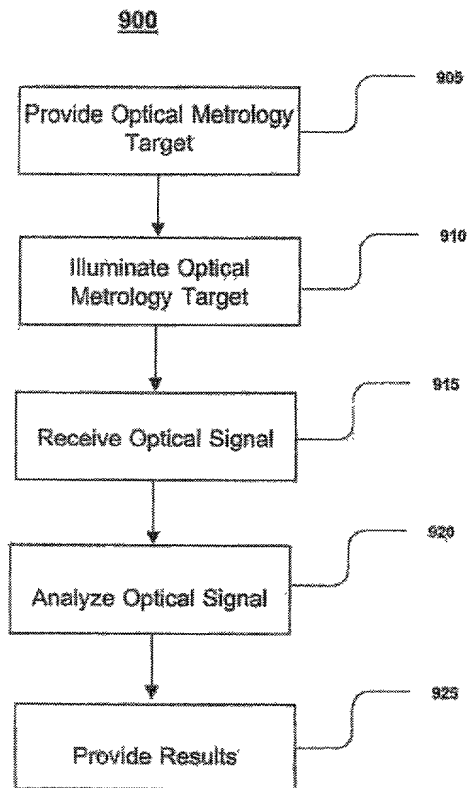
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Figure 8.



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OPTICAL METROLOGY TARGET DESIGN FOR  
SIMULTANEOUS MEASUREMENT OF MULTIPLE PERIODIC  
STRUCTURES**Fig. 9**